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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Hisashi Ohtani

Art Unit : 2822

Serial No.: 10/657,137

Examiner: Ida M. Soward

Filed

: September 9, 2003

Title

: SEMICONDUCTOR INTEGRATED CIRCUIT AND FABRICATION METHOD

THEREOF

MAIL STOP RCE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date: May 12, 2005

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Substitute Disclosure Form (PTO-1449)

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137	OIPA		
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hisashi Ohtani				
		Filing Date September 9, 2003	Group Art Unit 2822	MAY 1 2 20		

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002-0179969	12/05/2002	MIYAZAKI et al.			07/12/2002
	AB	2003-0094656	05/22/2003	KOYAMA et al.			11/18/2002
	AC	2003-0173570	09/18/2003	YAMAZAKI et al.			03/18/2003
	AD	2004-0023445	02/05/2004	MIYAZAKI et al.			07/17/2003
	AE	2004-0051102	03/18/2004	MIYAZAKI et al.			08/15/2003
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)				
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	AQ			
	AR			
	AS			
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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if no	ot in conformance and not considered. Include copy of this form with
next communication to applicant.	0.1.11.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.